

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/028,580 | Applicant(s)/Patent Under Reexamination JANES ET AL. | |
| | Examiner M. Scott Lowe | Art Unit 3652 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,158,949 | 12-2000 | Walth et al. | 414/722 |
| | B | US-6,409,459 | 06-2002 | Ginn et al. | 414/685 |
| | C | US-4,428,173 | 01-1984 | Knell, Harvey A. | 52/731.6 |
| | D | US-5,152,659 | 10-1992 | Waka, Toshihiko | 414/722 |
| | E | US-6,071,033 | 06-2000 | Neitzel et al. | 403/158 |
| | F | US-5,806,313 | 09-1998 | Koshi et al. | 60/458 |
| | G | US-4,214,923 | 07-1980 | Price, Robert J. | 148/529 |
| | H | US-5,993,139 | 11-1999 | Deneve et al. | 414/722 |
| | I | US-5,111,602 | 05-1992 | Risch, Joel V. | 37/406 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.